



Designation: E827-02 Designation: E 827 - 07

Standard Practice for Identifying Elements by the Peaks in Auger Electron Spectroscopy¹

This standard is issued under the fixed designation E 827; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This practice outlines the necessary steps for the identification of elements in a given Auger spectrum obtained using conventional electron spectrometers. Spectra displayed as either the electron energy distribution (direct spectrum) or the first derivative of the electron energy distribution are considered.

1.2 This practice applies to Auger spectra generated by electron or X-ray bombardment of the specimen surface and can be extended to spectra generated by other methods such as ion bombardment.

1.3

1.3 The values stated in SI units are to be regarded as standard. No other units of measurement are included in this standard.

1.4 This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.

2. Referenced Documents

2.1 ASTM Standards:²

E 673 Terminology Relating to Surface Analysis

E 983 Guide for Minimizing Unwanted Electron Beam Effects in Auger Electron Spectroscopy

E 984 Guide for Identifying Chemical Effects and Matrix Effects in Auger Electron Spectroscopy

E 1523 Guide to Charge Control and Charge Referencing Techniques in X-Ray Photoelectron Spectroscopy

3. Terminology

3.1 Terms used in Auger electron spectroscopy are defined in Terminology E 673.

4. Summary of Practice

4.1 The Auger spectrum is obtained with appropriate instrumental parameters from a low kinetic energy limit of approximately 30 eV to an upper kinetic energy limit of approximately 2000 to 3000 eV or higher to include all the principal Auger electron energies of all elements (except H and He which do not have Auger transitions).

4.2 This practice assumes the existence of appropriate reference spectra from pure element or stoichiometric compound standards, or both, with which an unknown spectrum can be compared (1, 2).³ It may be useful to note that although Auger energies in some data bases are referenced to the Fermi level, other data collections have been referenced to the vacuum level. Auger kinetic energies referenced to the Fermi level would be approximately 5 eV larger than values referenced to the vacuum level.

4.3 An element in an Auger spectrum is considered positively identified if the peak shapes, the peak energies, and the relative signal strengths of peaks from the unknown coincide with those from a standard reference spectrum of the element or compound.

5. Significance and Use

5.1 Auger analysis is used to determine the elemental composition of the first few several atomic layers, typically 0.51 to 2.05

¹ This practice is under the jurisdiction of ASTM Committee E42 on Surface Analysis and is the direct responsibility of Subcommittee E42.03 on Auger Electron Spectroscopy and XPS.

Current edition approved April 10, 2002. Published April 2002. Originally published as E827-81. Last previous edition E827-95.

² This practice is under the jurisdiction of ASTM Committee E42 on Surface Analysis and is the direct responsibility of Subcommittee E42.03 on Auger Electron Spectroscopy and X-Ray Photoelectron Spectroscopy.

Current edition approved Oct. 1, 2007. Published December 2007. Originally approved in 1981. Last previous edition approved in 2002 as E 827 - 02.

³ For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For Annual Book of ASTM Standards, Vol 03.06, volume information, refer to the standard's Document Summary page on the ASTM website.

³ The boldface numbers in parentheses refer to the list of references at the end of this standard.

nm thick, of a specimen surface. In conjunction with inert gas ion sputtering, it is used to determine the sputter depth profile to a depth of a few micrometres.

5.2 The specimen is normally a solid conductor, semiconductor, or insulator. For insulators, provisions may be required for control of charge accumulation at the surface (see Guide E 1523). Typical applications include the analysis of surface contaminants, thin film deposits or segregated overlayers on metallic or alloy substrates. The specimen topography may vary from a smooth, polished specimen to a rough fracture surface.

5.3 Auger analysis of specimens with volatile species that evaporate in the ultra-high vacuum environment of the Auger chamber and substances which are susceptible to electron or X-ray beam damage, such as organic compounds, may require special techniques not covered herein. (See Guide E 983.)

6. Apparatus

6.1 *Electron Energy Analyzers*; a retarding field analyzer, cylindrical mirror analyzer (single or double pass), or hemispherical analyzer is typically used.

6.2 *Standard Equipment*; typically an electron gun or X-ray source is used for excitation, an electron multiplier is used for amplification of the Auger electron signal, and a recording device is used to output the data.

6.2.1 A vacuum capability in the test chamber is required for operation of the electron gun or X-ray source and the spectrometer, and to allow analysis without contamination from the ambient atmosphere; gases; depending on specimen surface conditions, analysis is performed in the pressure range from 10^{-3} to 10^{-8} Pa.

7. Procedure

7.1 Identify the peak having the largest signal strength in the spectrum and note its peak energy and characteristic shape. Note that by convention, the peak energy is measured at the energy of the maximum intensity in the direct $N(E)$ spectrum and at the minimum value in the derivative spectrum. These two energies are generally will not be the same, with the derivative spectrum giving higher peak energies.

7.2 Consult a list of peak energies for elements and note the possible energy matches. The peak position can vary by up to 20 eV because of slightly differing chemistries, so include elements within a wide range of energies around the peak position noted in 7.1.

7.3 Consult the standard elemental spectrum for one of the elements identified by 7.2, ~~and look for the presence of additional lines in the specimen spectrum that match the standard spectrum~~, **and look for the presence of additional lines in the specimen spectrum that match the standard spectrum in energy and intensity (see peak overlap in 8.1.1) (1, 2). Direct and derivative standard spectra are available (1, 2). Compare the shape of the peaks as well. If a good match is found, label all lines from the standard spectrum that are visible in the specimen spectrum. If a match is not found, eliminate that element from further consideration and select another element from the list found in 7.2 and repeat 7.3.**

7.4 If all of the elements from 7.2 have been exhausted, widen the energy range and choose additional elements. Remember, charging may shift the energy spectrum substantially. In this event, look for the carbon and oxygen peak shapes (or other known elements) by shape and relative position to determine the extent of charging. Correct for charging and repeat 7.2 and 7.3.

7.5 If a match is still not found, temporarily ignore the most intense peak and repeat 7.1-7.3 for the next most intense peak. Recall that relative Auger peak intensities may change because of the specimen chemistry. A weaker peak may become more intense and the primary peak may become less intense. (See Guide E 984.)

7.6 Repeat 7.1-7.3 with peaks of decreasing signal strength until all peaks are positively identified.

7.7 It should be noted that since the Auger signal strength varies proportionally with the concentration of the element detected, an element present at a small concentration may register only its strongest Auger peak(s). The identification of such weak peaks should be verified by optimizing the signal-to-noise ratio in separate scans, for example, by repetitive scans of the energy range of interest.

7.8 When extending the technique to Auger transitions generated by an X-ray source, it is important to note that the kinetic energy of the Auger electrons does not change when the energy of the incident X-rays is changed. This may allow the Auger peaks to be distinguished from the photoelectron peaks.

7.9 Auger features generated by incident ions may have relative intensities and energies that differ substantially from those generated by electrons or X-rays (3).

8. Interferences

8.1 The procedure for positive elemental identification given in Section 7 is valid except when the characteristic shape of an Auger peak is subject to change (which is not caused by instrumental parameters such as different analyzer resolutions). This can arise from two situations:

8.1.1 Peak overlap occurs when Auger peak energies from two or more different elements coincide within the energy width ranges of the peaks. The spectrum of a possible component element can be subtracted from the composite data. This subtraction or spectrum stripping can be performed numerically, and the residual intensity can be compared with reference spectra for another possible element (4). Sometimes, for qualitative analysis, spectrum stripping can be adequately performed by an experienced eye. It may be necessary to take additional data on an expanded scale (perhaps with increased energy resolution and improved